

L Number	Hits	Search Text	DB	Time stamp
2	1211	702/118,119,117,81,82,87,84.ccls.	USPAT; US-PGPUB	2004/01/07 12:39
3	1172	700/224,226,116,95,109,115,117.ccls.	USPAT; US-PGPUB	2004/01/07 12:40
4	2557	438/5,10,14,16,17.ccls.	USPAT; US-PGPUB	2004/01/07 12:40
5	470	209/573,571.ccls.	USPAT; US-PGPUB	2004/01/07 12:40
6	5249	702/118,119,117,81,82,87,84.ccls. or 700/224,226,116,95,109,115,117.ccls. or 438/5,10,14,16,17.ccls. or 209/573,571.ccls.	USPAT; US-PGPUB	2004/01/07 12:40

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6067507 99  
6208947 99  
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6400840 99  
6588854 99  
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5907492 91  
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5856923 76  
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6350959 76  
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6437271 76  
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10600148\_CLS  
Most Frequently Occurring Classifications of Patents Returned  
From A Search of 10600148 on December 31, 2003

Original Classifications

10	209/573
7	700/121
6	324/758
4	324/765
4	382/145
4	702/118
4	714/724
2	438/14

Cross-Reference Classifications

13	257/E23.179
13	324/765
10	209/571
9	700/116
7	324/158.1
6	257/E23.004
5	257/E21.512
5	257/E21.525
5	438/14
5	700/224
5	702/187
5	702/82
4	324/755
4	700/226
4	702/117
3	324/758
3	324/763
3	438/17
3	714/704
2	209/583
2	324/704
2	700/108
2	700/109
2	700/117
2	700/215
2	702/118

Combined Classifications

17	324/765
13	257/E23.179
11	209/573
10	209/571
9	324/758

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9 700/116  
8 700/121  
7 324/158.1  
7 438/14  
6 257/E23.004  
6 702/118  
5 257/E21.512  
5 257/E21.525  
5 324/755  
5 382/145  
5 700/224  
5 702/187  
5 702/82  
4 700/226  
4 702/117  
4 714/704  
4 714/724  
3 324/763  
3 438/17  
2 209/583  
2 324/704  
2 324/760  
2 700/108  
2 700/109  
2 700/117  
2 700/215

10600148\_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 10600148 on December 31, 2003

17	324/765	(4 OR, 13 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING
	324/500	FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
	324/537	.Of individual circuit component or element
	324/765	..Test of semiconductor device
13	257/E23.179	(0 OR, 13 XR)
	Class 257 :	ACTIVE SOLID-STATE DEVICES
	257/E23.176	...For flat cards, e.g., credit cards (EPO)
	257/E23.179	.Marks applied to semiconductor devices or parts, e.g., registration marks, test patterns, alignment structures, wafer maps (EPO)
11	209/573	(10 OR, 1 XR)
	Class 209 :	CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS
	209/509	SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE SORTING, ETC.) FOR SORTING ANY ITEMS
	209/552	.Condition responsive means controls separating means
	209/571	..Electrical test sensing property of item
	209/573	...Electrical component tested
10	209/571	(0 OR, 10 XR)
	Class 209 :	CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS
	209/509	SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE SORTING, ETC.) FOR SORTING ANY ITEMS
	209/552	.Condition responsive means controls separating means
	209/571	..Electrical test sensing property of item
9	324/758	(6 OR, 3 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING
	324/500	FAULT DETECTING IN ELECTRIC CIRCUITS AND OF

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ELECTRIC COMPONENTS

324/537 .Of individual circuit component or element  
324/754 ..With probe elements  
324/758 ...Probe alignment or positioning

9 700/116 (0 OR, 9 XR)  
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR  
SPECIFIC APPLICATIONS  
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS  
700/95 .Product assembly or manufacturing  
700/115 ..Product tracking (e.g., having product or  
carrier identification)  
700/116 ...Having identification controlled  
manufacturing operation

8 700/121 (7 OR, 1 XR)  
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR  
SPECIFIC APPLICATIONS  
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS  
700/95 .Product assembly or manufacturing  
700/117 ..Particular manufactured product or operation  
700/121 ...Integrated circuit production or  
semiconductor fabrication

7 324/158.1 (0 OR, 7 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/158.1 MISCELLANEOUS

7 438/14 (2 OR, 5 XR)  
Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS  
438/14 WITH MEASURING OR TESTING

6 257/E23.004 (0 OR, 6 XR)  
Class 257 : ACTIVE SOLID-STATE DEVICES  
257/E23.001 PACKAGING, INTERCONNECTS, AND MARKINGS FOR  
SEMICONDUCTOR OR OTHER SOLID-STATE DEVICE  
S (EPO)  
257/E23.003 .Mountings, e.g., nondetachable insulating  
substrates (EPO)  
257/E23.004 ..Characterized by shape (EPO)

6 702/118 (4 OR, 2 XR)  
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR  
TESTING  
702/108 TESTING SYSTEM  
702/117 .Of circuit

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702/118 ..Testing multiple circuits

5 257/E21.512 (0 OR, 5 XR)

Class 257 : ACTIVE SOLID-STATE DEVICES

257/E21.001 PROCESSES OR APPARATUS ADAPTED FOR MANUFACTURE

OR TREATMENT OF SEMICONDUCTOR OR SOL

ID-STATE DEVICES OR OF

PARTS THEREOF (EPO)

257/E21.002 .Manufacture or treatment of semiconductor device (EPO)

257/E21.04 ..Device having at least one potential-jump barrier or surface barrier, e.g., PN junction, depletion layer, carrier concentration layer (EPO)

257/E21.499 ...Assembling semiconductor devices, e.g., packaging, including mounting, encapsulating, or treatment of packaged semiconductor (EPO)

257/E21.506 ....Attaching or detaching leads or other conductive members, to be used for carrying current to or from device in operation (EPO)

257/E21.509 .....Involving soldering or alloying process, e.g., soldering wires (EPO)

257/E21.511 .....Mounting on insulating member provided with metallic leads, e.g., flip-chip mounting, conductive die mounting (EPO)

257/E21.512 .....Right-up bonding (EPO)

5 257/E21.525 (0 OR, 5 XR)

Class 257 : ACTIVE SOLID-STATE DEVICES

257/E21.515 .....Involving use of mechanical auxiliary parts without use of alloying or soldering process, e.g.,

pressure contacts (EPO)

257/E21.521 .Testing or measuring during manufacture or treatment or reliability measurement, i.e.,

, testing of parts followed by no processing which modifies parts as such (EPO)

257/E21.525 ..Procedures, i.e., sequence of activities consisting of plurality of measurement and correction,



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marking or sorting steps (EPO)

5 324/755 (1 OR, 4 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
ELECTRIC COMPONENTS  
324/537 .Of individual circuit component or element  
324/754 ..With probe elements  
324/755 ...Internal of or on support for device under  
test (DUT)

5 382/145 (4 OR, 1 XR)  
Class 382 : IMAGE ANALYSIS  
382/100 APPLICATIONS  
382/141 .Manufacturing or product inspection  
382/145 ..Inspection of semiconductor device or printed

d  
circuit board

5 700/224 (0 OR, 5 XR)  
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR  
SPECIFIC APPLICATIONS  
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS  
700/213 .Article handling  
700/219 ..Associating or disassociating plural article

s  
700/223 ...Collating or sorting  
700/224 ....Having an identification code

5 702/187 (0 OR, 5 XR)  
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR  
TESTING  
702/127 MEASUREMENT SYSTEM  
702/187 .History logging or time stamping

5 702/82 (0 OR, 5 XR)  
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR  
TESTING  
702/1 MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT  
702/81 .Quality evaluation  
702/82 ..Having judging means (e.g., accept/reject)

4 700/226 (0 OR, 4 XR)  
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR  
SPECIFIC APPLICATIONS  
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS  
700/213 .Article handling

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700/225 ..Having an identification code

700/226 ...Identification code determines article destination

4 702/117 (0 OR, 4 XR)

Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR TESTING

702/108 TESTING SYSTEM

702/117 .Of circuit

4 714/704 (1 OR, 3 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/704 .Error count or rate

4 714/724 (4 OR, 0 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

3 324/763 (0 OR, 3 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING

324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS

324/537 .Of individual circuit component or element

324/763 ..DUT including test circuit

3 438/17 (0 OR, 3 XR)

Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS

438/14 WITH MEASURING OR TESTING

438/17 .Electrical characteristic sensed

2 209/583 (0 OR, 2 XR)

Class 209 : CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS

209/509 SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE SORTING, ETC.) FOR SORTING ANY ITEMS

209/552 .Condition responsive means controls separatin

g means

209/576 ..Sensing radiant energy reflected, absorbed, emitted, or obstructed by item or adjunct thereof

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209/577 ...Infrared, visible light, or ultraviolet

209/583 ....Reading indicia

2 324/704 (0 OR, 2 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING

324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES

REPRESENTATIVE OF ELECTRICAL STIMULUS/RE

SPONSE

RELATIONSHIPS

324/649 .Lumped type parameters

324/691 ..Using resistance or conductance measurement

324/704 ...With ratio determination

2 324/760 (1 OR, 1 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING

324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF

ELECTRIC COMPONENTS

324/537 .Of individual circuit component or element

324/754 ..With probe elements

324/760 ...With temperature control

2 700/108 (0 OR, 2 XR)

Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR

SPECIFIC APPLICATIONS

700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS

700/95 .Product assembly or manufacturing

700/108 ..Performance monitoring

2 700/109 (0 OR, 2 XR)

Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR

SPECIFIC APPLICATIONS

700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS

700/95 .Product assembly or manufacturing

700/108 ..Performance monitoring

700/109 ...Quality control

2 700/117 (0 OR, 2 XR)

Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR

SPECIFIC APPLICATIONS

700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS

700/95 .Product assembly or manufacturing

700/117 ..Particular manufactured product or operation

2 700/215 (0 OR, 2 XR)

Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR

SPECIFIC APPLICATIONS

10600148 CLSTITLES  
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS  
700/213 .Article handling  
700/214 ..Article storing, retrieval, or arrangement  
(e.g., warehousing, automated library)  
700/215 ...Having an identification code